## Notice of References Cited

Application/Control No.

O9/839,794

Examiner

Sargon N Nano

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Art Unit
Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,725,264	04-2004	Christy, James Edwin	709/225
	В	US-6,560,630	05-2003	Vepa et al.	718/105
	С	US-6,535,510	03-2003	Kalkunte et al.	370/389
	D	US-6,590,861	07-2003	Vepa et al.	370/216
	E	US-6,389,448	05-2002	Primak et al.	718/105
	F	US-6,397,260	05-2002	Wils et al.	709/238
	G	US-6,195,680	02-2001	Goldszmidt et al.	709/203
	Н	US-6,175,874	01-2001	Imai et al.	709/238
	ı	US-			
	J	US-			
-	К	US-		·	
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q			:		
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
_	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.